

Search Notes

Application/Control No.

10/669,503

Examiner

Yong D. Pak

Applicant(s)/Patent under
Reexamination

KAWANO ET AL.

Art Unit

1652

SEARCHED

Class	Subclass	Date	Examiner
435	189	6/28/2006	YP
435	4	6/28/2006	YP
435	6	6/28/2006	YP
435	25	6/28/2006	YP
435	18	6/28/2006	YP
435	69.1	6/28/2006	YP
435	71.1	6/28/2006	YP
435	440	6/28/2006	YP
536	23.2	6/28/2006	YP
536	23.7	6/28/2006	YP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
stic: seq id no:1, oligomer search of SEQ ID NO:1	6/28/2006	YP
str/east: see search history	6/28/2006	YP
inventor search	6/28/2006	YP